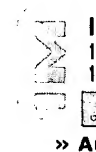| Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	309	((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:14
L2	3	l1 same ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:26
L3	1	l1 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:34
L4	5	l1 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:14
L5	103	((transfer or transfer or transmit$4 or transmission)near4 (encoded near3(data with clock)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:34
L6	11	l5 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:34
L7	0	l6 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:15
L8	0	l5 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:35

L9	0	I5 and (((multiple or plural$4)near3 read)same ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:35
L10	2	"4454499".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:46
L11	100	"5268937" "4454499" "5912928" "5528183" "5841481" "6424631" "3775751" "6097716" "6222875" "6509988" "52260125,623,522" U5-6,313,879.pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:48
L12	101	"5268937" "4454499" "5912928" "5528183" "5841481" "6424631" "3775751" "6097716" "6222875" "6509988" "52260125" "63138795"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:49
L13	22	("5268937" "4454499" "5912928" "5528183" "5841481" "6424631" "3775751" "6097716" "6222875" "6509988" "52260125" "63138795").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:14
L14	30	("6061747" "6320825" "5446765" "5850574" "6269127" "3864735" "4063291" "6104697" "5651014" "4796280" "6292621" "5412697" "5381397").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:55
L15	6	"5226012"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:52
L16	4	("5226012" "5226012" "6313879").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:54

L17	6	("5226012" "5623522" "6313879").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 07:54
L18	23496	"713"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:19
L19	316	l18 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:19
L20	6	l18 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:21
L21	2	l19 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:19
L22	92419	"369"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:23
L23	518	l22 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:23
L24	4	l23 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:24

L25	9	I22 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:24
L26	102048	"360"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:25
L27	530	I26 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:25
L28	25	I26 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L29	3	I27 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:27
L30	2	I28 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L31	65870	"348"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L32	17	I31 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28

L33	767	I31 and (((determin$4 or detect$4 or select$4))with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L34	0	I32 and I33	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:26
L35	2	I33 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L36	57397	"375"/$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L37	7	I36 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51
L38	4	I36 and (((multiple or plural$4)near3 read)with ((transfer or transfer or transmit$4 or transmission)near3 (speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:28
L39	42	(decoder or encoder)with ((detect$4 or determin$5)near3 (transfer adj2(speed or rate)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:50
L40	1	I39 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))with ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51

L41	1	I39 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))same ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51
L42	1	I39 and (((select$4 or choos$4)near5 (read near3 (clock or strobe or signal)))and ((multiple or plural$4)adj5 read))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/08 08:51

◈IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE Xplore®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

Help   FAQ   Terms   IEEE Peer Review   **Quick Links**   ▼

» Au

Welcome to IEEE Xplore®

○– Home
○– What Can
     I Access?
○– Log-out

Tables of Contents

○– Journals
     & Magazines
○– Conference
     Proceedings
○– Standards

Search

○– By Author
○– Basic
○– Advanced
○– CrossRef

Member Services

○– Join IEEE
○– Establish IEEE
     Web Account
○– Access the
     IEEE Member
     Digital Library

IEEE Enterprise

○– Access the
     IEEE Enterprise
     File Cabinet

Try our New Full-text Search Prototype GO   Help

To Locate an Author:
1. Enter a last name or select a letter in the alphabet.
2. Once you identify the name, select it to search the database for relevant articles.

1.Options:
» Enter a name to find an author:

[   ] Go

Example: Enter Lockett S to obtain a list of authors with the last name Lockett and first name initial S.
OR» Select a letter to browse the author list:

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

2. Select an author name to search the database for relevant articles:

No Authors Found with beginning letter: ueno hirotaka

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

◆IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

IEEE *Xplore*®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

» Au

Help   FAQ   Terms   IEEE Peer Review   **Quick Links**

Welcome to IEEE *Xplore*®

O- Home
O- What Can
    I Access?
O- Log-out

Tables of Contents

O- Journals
   & Magazines
O- Conference
   Proceedings
O- Standards

Search

O- By Author
O- Basic
O- Advanced
O- CrossRef

Member Services

O- Join IEEE
O- Establish IEEE
   Web Account
O- Access the
   IEEE Member
   Digital Library

IEEE Enterprise

O- Access the
   IEEE Enterprise
   File Cabinet

Try our New Full-text Search Prototype GO   Help

To Locate an Author:

1. Enter a last name or select a letter in the alphabet.
2. Once you identify the name, select it to search the database for relevant articles.

1.Options:

» Enter a name to find an author:

[   ]   Go

Example: Enter Lockett S to obtain a list of authors with the last name Lockett and first name initial S.
OR» Select a letter to browse the author list:

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

2. Select an author name to search the database for relevant articles:

No Authors Found with beginning letter: hirotaka ueno

A B C D E F G H I J K L M N O P Q R S T U V W X Y Z | ALL

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

◆IEEE

Membership   Publications/Services   Standards   Conferences   Careers/Jobs

IEEE *Xplore*®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

» Se

Help   FAQ   Terms   IEEE Peer Review   **Quick Links**

Welcome to IEEE *Xplore*®

O— Home
O— What Can
I Access?
O— Log-out

Tables of Contents

O— Journals
& Magazines
O— Conference
Proceedings
O— Standards

Search

O— By Author
O— Basic
O— Advanced
O— CrossRef

Member Services

O— Join IEEE
O— Establish IEEE
Web Account
O— Access the
IEEE Member
Digital Library

IEEE Enterprise

O— Access the
IEEE Enterprise
File Cabinet

🖳 Print Format

Your search matched **61** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

1 **Corona and breakdown characteristics between sphere electrode wi protrusion and plane electrode under negative pulse voltage in N/sub gas**
Ueno, H.; Sakomoto, N.; Hoshida, T.; Nakayama, H.;
Dielectrics and Electrical Insulation, IEEE Transactions on [see also Electrical Insulation, IEEE Transactions on] ,Volume: 11 , Issue: 6 , Dec. 2004
Pages:1065 - 1072

[Abstract]   [PDF Full-Text (1659KB)]   **IEEE JNL**

2 **Impurity-profile-based threshold-voltage model of pocket-implante(MOSFETs for circuit simulation**
Ueno, H.; Kitamaru, D.; Morikawa, K.; Tanaka, M.; Miura-Mattausch, M.; Mattausch, H.J.; Kumashiro, S.; Yamaguchi, T.; Yamashita, K.; Nakayama, N.
Electron Devices, IEEE Transactions on ,Volume: 49 , Issue: 10 , Oct. 2002
Pages:1783 - 1789

[Abstract]   [PDF Full-Text (339KB)]   **IEEE JNL**

3 **Importance of ballistic carriers for the dynamic response in sub-100 MOSFETs**
Okagaki, T.; Tanaka, M.; Ueno, H.; Miura-Mattausch, M.;
Electron Device Letters, IEEE ,Volume: 23 , Issue: 3 , March 2002
Pages:154 - 156

[Abstract]   [PDF Full-Text (237KB)]   **IEEE JNL**

4 **Fabrication of thick film magnetic cores for high frequency using LI(process**
Takimoto, S.; Ueno, H.; Sugiyama, S.; Yamaguchi, M.; Baba, M.; Arai, K.-I.;
Magnetics, IEEE Transactions on ,Volume: 37 , Issue: 4 , July 2001
Pages:2888 - 2890

[Abstract]   [PDF Full-Text (160KB)]   **IEEE JNL**

5 **Anomalous creeping flashover characteristics in N_2/SF_6 mixed gas**

under single pulse voltage
Ueno, H.; Sakamoto, N.; Nakayama, H.;
Dielectrics and Electrical Insulation, IEEE Transactions on [see also Electrical
Insulation, IEEE Transactions on] ,Volume: 8 , Issue: 2 , April 2001
Pages:195 - 202

[Abstract]   [PDF Full-Text (752KB)]   **IEEE JNL**

---

6 **An experimental M2DFE detector**
Yuan Xing Lee; Qingwei Jia; Jianjiang Wang; Qing Li; Lei Bi; Ueno, H.; Mutoh,
Magnetics, IEEE Transactions on ,Volume: 35 , Issue: 5 , Sept. 1999
Pages:2292 - 2294

[Abstract]   [PDF Full-Text (260KB)]   **IEEE JNL**

---

7 **A method for suppressing error propagation in (1,7) MDFE detectors**
Ueno, H.; Sugawara, T.; Shimoda, K.; Mutoh, H.;
Magnetics, IEEE Transactions on ,Volume: 35 , Issue: 5 , Sept. 1999
Pages:2289 - 2291

[Abstract]   [PDF Full-Text (320KB)]   **IEEE JNL**

---

8 **PdPtMn/CoFeB synthetic ferrimagnet spin-valve heads**
Kanai, H.; Kanamine, M.; Hashimoto, A.; Aoshima, K.; Noma, K.; Yamagishi,
Ueno, H.; Uehara, Y.; Uematsu, Y.;
Magnetics, IEEE Transactions on ,Volume: 35 , Issue: 5 , Sept. 1999
Pages:2580 - 2582

[Abstract]   [PDF Full-Text (340KB)]   **IEEE JNL**

---

9 **Rigid disk medium for 20 Gb/in^2 recording demonstration**
Sato, K.; Yoshida, Y.; Yamagishi, M.; Ueno, H.; Akimoto, H.; Abarra, E.N.; Ka
H.; Uehara, Y.; Okamoto, I.; Uematsu, Y.;
Magnetics, IEEE Transactions on ,Volume: 35 , Issue: 5 , Sept. 1999
Pages:2655 - 2657

[Abstract]   [PDF Full-Text (264KB)]   **IEEE JNL**

---

10 **An experimental MDFE detector**
Hong, J.; Yuan Xing Lee; Mutoh, H.; Qicheng Sun; Ueno, H.; Jianjiang Wang;
Wood, R.;
Magnetics, IEEE Transactions on ,Volume: 33 , Issue: 5 , Sept. 1997
Pages:2776 - 2778

[Abstract]   [PDF Full-Text (276KB)]   **IEEE JNL**

---

11 **A novel proportional counter made of a capillary plate**
Tamura, T.; Sakurai, H.; Noma, M.; Gunji, S.; Ueno, H.; Tsukahara, M.; Ham
M.;
Nuclear Science, IEEE Transactions on ,Volume: 43 , Issue: 3 , June 1996
Pages:1533 - 1538

[Abstract]   [PDF Full-Text (460KB)]   **IEEE JNL**

---

12 The energy resolution of proportional counters with thin anode diameters down to 5 μm
Tokanai, F.; Sakurai, H.; Noma, M.; Gunji, S.; Ueno, H.; Anzai, T.; Kato, F.; Hoshina, T.;
Nuclear Science, IEEE Transactions on ,Volume: 41 , Issue: 4 , Aug 1994
Pages:1042 - 1047

[Abstract]   [PDF Full-Text (416KB)]   **IEEE JNL**

---

13 Arc-discharge mode and interruption performance in vacuum switc tubes
Toya, H.; Hayashi, T.; Okumura, M.; Yorita, M.; Ueno, H.;
Power Delivery, IEEE Transactions on ,Volume: 7 , Issue: 1 , Jan. 1992
Pages:324 - 331

[Abstract]   [PDF Full-Text (584KB)]   **IEEE JNL**

---

14 Polymer based smart flexible thermopile for power generation
Hasebe, S.; Ogawa, J.; Shiozaki, M.; Toriyama, T.; Sugiyama, S.; Ueno, H.; Itoigawa, K.;
Micro Electro Mechanical Systems, 2004. 17th IEEE International Conference (
(MEMS) , 2004
Pages:689 - 692

[Abstract]   [PDF Full-Text (1457KB)]   **IEEE CNF**

---

15 Study of partial discharge localization methods for EHV prefabricat joint
Chen Min; Urano, K.; Kato, A.; Sakaguchi, Y.; Okamoto, G.; Ueno, H.; Hirotu, Jinno, A.; Okada, M.; Yoshikawa, N.;
Power Engineering Society Summer Meeting, 2000. IEEE ,Volume: 1 , 16-20
2000
Pages:475 - 479 vol. 1

[Abstract]   [PDF Full-Text (424KB)]   **IEEE CNF**

---

1 2 3 4 5 Next

IEEE *Xplore*®
RELEASE 1.8

Help   FAQ   Terms   IEEE Peer Review | **Quick Links** |

» Se

Welcome to IEEE *Xplore*®

- ○ Home
- ○ What Can I Access?
- ○ Log-out

Tables of Contents

- ○ Journals & Magazines
- ○ Conference Proceedings
- ○ Standards

Search

- ○ By Author
- ○ Basic
- ○ Advanced
- ○ CrossRef

Member Services

- ○ Join IEEE
- ○ Establish IEEE Web Account
- ○ Access the IEEE Member Digital Library

IEEE Enterprise

- ○ Access the IEEE Enterprise File Cabinet

🖳 Print Format

Your search matched **61** documents.

A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Results Key:
JNL = Journal or Magazine   **CNF** = Conference   **STD** = Standard

---

16 **Fabrication of sub-micron structures with high aspect ratio for MEN using deep X-ray lithography**
Ueno, H.; Nishi, N.; Sugiyama, S.;
Micro Electro Mechanical Systems, 2000. MEMS 2000. The Thirteenth Annual International Conference on , 23-27 Jan. 2000
Pages:596 - 601

[Abstract]   [PDF Full-Text (664KB)]   IEEE CNF

---

17 **Direct writing for three-dimensional microfabrication using synchro radiation etching**
Katoh, T.; Nishi, N.; Fukagawa, M.; Ueno, H.; Sugiyama, S.;
Micro Electro Mechanical Systems, 2000. MEMS 2000. The Thirteenth Annual International Conference on , 23-27 Jan. 2000
Pages:556 - 561

[Abstract]   [PDF Full-Text (480KB)]   IEEE CNF

---

18 **Genetic algorithm accelerator GAA-II**
Wakabayashi, S.; Koide, T.; Toshine, N.; Yamane, M.; Ueno, H.;
Design Automation Conference, 2000. Proceedings of the ASP-DAC 2000. Asia South Pacific , 25-28 Jan. 2000
Pages:9 - 10

[Abstract]   [PDF Full-Text (204KB)]   IEEE CNF

---

19 **Study on fabrication of high aspect ratio microparts using the LIGA process**
Ueno, H.; Hosaka, M.; Zhang, Y.; Tabata, O.; Konishi, S.; Sugiyama, S.;
Micromechatronics and Human Science, 1997. Proceedings of the 1997 International Symposium on , 5-8 Oct. 1997
Pages:49 - 54

[Abstract]   [PDF Full-Text (592KB)]   IEEE CNF

---

20 **An Experimental MDFE Detector**

Bi, L.; Hong, J.; Lee, Y.X.; Mutoh, H.; Sun, Q.C.; Ueno, H.; Wang, J.J.; Wood,
Magnetics Conference, 1997. Digests of INTERMAG '97., 1997 IEEE
International , 1-4 April 1997
Pages:CR-05 - CR-05

[Abstract]   [PDF Full-Text (92KB)]   **IEEE CNF**

21 Development of Nissan's ASV
Sugasawa, F.; Ueno, H.; Kaneda, M.; Koreishi, J.; Shirato, R.; Fukuhara, N.;
Intelligent Vehicles Symposium, 1996., Proceedings of the 1996 IEEE , 19-20
1996
Pages:254 - 259

[Abstract]   [PDF Full-Text (504KB)]   **IEEE CNF**

22 A compact SR beamline for fabrication of high aspect ratio MEMS microparts
Sugiyama, S.; Zhang, Y.; Ueno, H.; Hosaka, M.; Fujimoto, T.; Maeda, R.; Tan
T.;
Micro Machine and Human Science, 1996., Proceedings of the Seventh
International Symposium , 2-4 Oct. 1996
Pages:79 - 84

[Abstract]   [PDF Full-Text (660KB)]   **IEEE CNF**

23 Low-k fluorinated amorphous carbon interlayer technology for quai micron devices
Matsubara, Y.; Endo, K.; Tatsumi, T.; Ueno, H.; Sugai, K.; Horiuchi, T.;
Electron Devices Meeting, 1996., International , 8-11 Dec. 1996
Pages:369 - 372

[Abstract]   [PDF Full-Text (432KB)]   **IEEE CNF**

24 Unique corona and creeping flashover characteristics in N/sub 2/ a N/sub 2//SF/sub 6/ mixtures on highly nonuniform narrow gap
Ueno, H.; Kawano, T.; Nishikawa, T.; Nakayama, H.;
Properties and Applications of Dielectric Materials, 2003. Proceedings of the 71
International Conference on ,Volume: 1 , 1-5 June 2003
Pages:232 - 237 vol.1

[Abstract]   [PDF Full-Text (456KB)]   **IEEE CNF**

25 Design and fabrication of flexible thermopile for power generation
Hasebe, S.; Ogawa, J.; Toriyama, T.; Sugiyama, S.; Ueno, H.; Itoigawa, K.;
Micromechatronics and Human Science, 2003. MHS 2003. Proceedings of 200:
International Symposium on , 19-22 Oct. 2003
Pages:287 - 291

[Abstract]   [PDF Full-Text (351KB)]   **IEEE CNF**

26 Temperature-independence-point properties for 0.1 /spl mu/m-sca pocket-implant technologies and the impact on circuit design
Hisamitsu, K.; Ueno, H.; Tanaka, M.; Kitamaru, D.; Miura-Mattausch, M.;

Mattausch, H.J.; Kumashiro, S.; Yamaguchi, T.; Yamashita, K.; Nakayama, N.
Design Automation Conference, 2003. Proceedings of the ASP-DAC 2003. Asia
South Pacific , 21-24 Jan. 2003
Pages:179 - 183

[Abstract]   [PDF Full-Text (475KB)]   **IEEE CNF**

---

27 **Microarchitecture and performance analysis of a SPARC-V9
microprocessor for enterprise server systems**
*Sakamoto, M.; Katsuno, A.; Inoue, A.; Asakawa, T.; Ueno, H.; Morita, K.; Kin
Y.;*
The Ninth International Symposium on High-Performance Computer Architectι
2003. HPCA-9 2003. Proceedings. , 8-12 Feb. 2003
Pages:141 - 152

[Abstract]   [PDF Full-Text (22890KB)]   **IEEE CNF**

---

28 **Circuit-simulation model of gate-drain-capacitance changes in sma
size MOSFETs due to high channel-field gradients**
*Navarro, D.; Hisamitsu, K.; Yamaoka, T.; Tanaka, M.; Kawano, H.; Ueno, H.;
Miura-Mattausch, M.; Mattausch, H.J.; Kumashiro, S.; Yamaguchi, T.; Yamash
K.; Nakayama, N.;*
Simulation of Semiconductor Processes and Devices, 2002. SISPAD 2002.
International Conference on , 4-6 Sept. 2002
Pages:51 - 54

[Abstract]   [PDF Full-Text (321KB)]   **IEEE CNF**

---

29 **HiSIM: a MOSFET model for circuit simulation connecting circuit
performance with technology**
*Miura-Mattausch, M.; Ueno, H.; Tanaka, M.; Mattausch, H.J.; Kumashiro, S.;
Yamaguchi, T.; Yamashita, K.; Nakayama, N.;*
Electron Devices Meeting, 2002. IEDM '02. Digest. International , 8-11 Dec. 2
Pages:109 - 112

[Abstract]   [PDF Full-Text (331KB)]   **IEEE CNF**

---

30 **Satellite capturing strategy using agile Orbital Servicing Vehicle, Hy
OSV**
Matsumoto, S.; Ohkami, Y.; Wakabayashi, Y.; Oda, M.; Ueno, H.;
Robotics and Automation, 2002. Proceedings. ICRA '02. IEEE International
Conference on ,Volume: 3 , 11-15 May 2002
Pages:2309 - 2314

[Abstract]   [PDF Full-Text (625KB)]   **IEEE CNF**

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top